

# Chip Multilayer Ceramic Capacitors for General



Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / IEC60384-14 Class X2

## **GA3 Series Type GB**







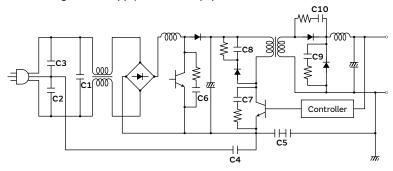
## IEC60384-14 X2 Class Certified Product

#### **Features**

**(1)** International Standard (IEC60384-14) certified product. Please down load Safety Standard Certification (Type GB: X2) from here. | WEB

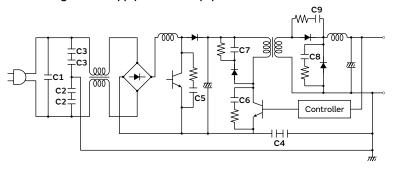
2 Can be used as a Class X2 capacitor.

Switching Power Supply - Class 1 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2		
С3	Y Cap	Type: GF
C4		
C5	Primary - Secondary Coupling	Type: GF×2

Switching Power Supply - Class 2 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2	Y Cap	
С3	т Сар	Type: GF×2
C4	Primary - Secondary Coupling	

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GR3

GRJ

GR4

GR7

G M

GQM

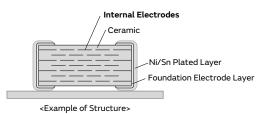
GA2

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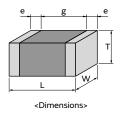
3 Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.



- 4 Compared with conventional lead type capacitors, this product realized great reductions in size and height, with a volume of 1/10 or less, and height of 1/4 or less.
- 5 This product is only for reflow soldering.

## Specifications

Size (mm)	5.7×5.0mm
Rated Voltage	250Vac
Capacitance	10000pF to 56000pF
Main Applications	AC-DC power supply



This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.

## GA3 Series Type GB High Dielectric Constant Type Part Number List

#### 5.7×5.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	p*
1.5mm	250Vac	X7R	10000pF	±10%	GA355QR7GB103KW01#	p192
			15000pF	±10%	GA355QR7GB153KW01#	p192
2.0mm	250Vac	X7R	22000pF	±10%	GA355DR7GB223KW01#	p192
2.5mm	250Vac	X7R	33000pF	±10%	GA355ER7GB333KW01#	p192
			47000pF	±10%	GA355ER7GB473KW01#	p192
2.9mm	250Vac	X7R	56000pF	±10%	GA355XR7GB563KW06#	p192

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## GA3 Series Type GB Specifications and Test Methods (1)

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)	
1	Appearance		No defects or abnormalities.	Visual inspection.	
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.	
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: DC1075V Applied Time: 60±1s Charge/discharge current: 50mA max.	
4	Insulation Resistance (I.R.)		$6000$ M $\Omega$ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature	
5	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature	
6	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)	
7	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage.  Capacitance value as a reference is the value in step 3.  Step Temperature (°C)  1 Reference Temp. ±2  2 Min. Operating Temp. ±3  3 Reference Temp. ±2  4 Max. Operating Temp. ±3  5 Reference Temp. ±2  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h. at room condition*.	
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in	
		Capacitance	Within the specified initial value.	"Complement of Test Method".  Kind of Vibration: A simple harmonic motion	
8	Vibration	D.F.	Within the specified initial value.	Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).	
9	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.	
		Appearance	No defects or abnormalities.	Test Method: Solder bath method	
		Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s	
	Resistance	I.R.	$1000$ M $\Omega$ or more	Immersion time: 10±15 Immersing in speed: 25±2.5mm/s.	
10	to Soldering Heat	Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.  Preheat: GA355 size: 100 to 120°C for 1min and 170 to 200°C for 1min  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.	
11	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".  10N, 10±1s  Applied Direction: In parallel with the test substrate and vertical with the capacitor side.	
12	2 Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method".  Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method".  Flexure: 1mm  Holding Time: 5±1s  Soldering Method: Reflow soldering	

 $<sup>{}^*\,</sup>Room\,Condition; Temperature: 15\,to\,35^\circ C,\,Relative\,humidity: 45\,to\,75\%,\,Atmosphere\,pressure: 86\,to\,106 kPa$ 

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## GA3 Series Type GB Specifications and Test Methods (1)

Continued from the preceding page.

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)		
		Appearance Capacitance Change	No defects or abnormalities.  Within±15%	Fix the capacitor to the supporting test substrate A (glass epoxy board) shown in "Complement of Test Method".  Perform the 5 cycles according to the four heat treatments shown in the following table.		
		D.F.	0.05 max.	Step Temp. (°C) Time (min)		
	Temperature	I.R.	3000MΩ or more	1 Min. Operating Temp. +0/-3 30±3		
13 Su	Sudden Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3  Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  • No.11 Adhesive Strength of Termination (apply force: 5N)		
	High	D.F.	0.05 max.	No.12 Substrate Bending Test		
14	Temperature High	I.R.	3000MΩ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH		
	Humidity (Steady)	Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass		
		Capacitance Change	Within ±20%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  • No.11 Adhesive Strength of Termination (apply force: 5N)		
		D.F.	0.05 max.	No.12 Substrate Bending Test		
		I.R.	3000M $Ω$ or more	Next, Impulse Voltage test is performed.  Each individual capacitor shall be subjected to a 2.5kV Impulse		
15	Durability	Voltage Proof	No defects.	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.  100 (%) 90 50 Front time (T1) = 1.2μs=1.67T Time to half-value (T2) = 50μs  Apply voltage as Table for 1000h at 125+2/-0°C, relative humidity 50% max.  Applied Voltage AC312.5V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s.  Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		

<sup>\*</sup> Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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## GA3 Series Type GB Specifications and Test Methods (1)

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Passive Flammability  The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.  Age of the proof of the paper shall not ignite.  The more than the paper shall not ignite and the paper shall not ignite.	e capacitor under test shall be held in the flame in the sition which best promotes burning. ch specimen shall only be exposed once to the flame. ne of exposure to flame: 30s ngth of flame: 12±1mm s burner: Length 35mm min. ided dia: 0.5±0.1mm tside dia: 0.9mm max. s: Butane gas purity 95% min.  Approximately 8mm  Buner  Flame  200±5mm
Passive Flammability  The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.  Age of the proof of the paper shall not ignite.  The more than the paper shall not ignite and the paper shall not ignite.	sition which best promotes burning. ch specimen shall only be exposed once to the flame. ne of exposure to flame: 30s ngth of flame: 12±1mm s burner: Length 35mm min. ide dia: 0.5±0.1mm tside dia: 0.9mm max. s: Butane gas purity 95% min.  Approximately 8mm Buner Flame 200+5mm
mor The The	→ Tissue Paper  Tissue Paper  Wood Board of Approximately 10mm in Thickness
The cheesecloth shall not be on fire.  C3: L1 t R: R Ct: T U-: U UR: Cx: C F: Sl	e specimens shall be individually wrapped in at least one but one than two complete layers of cheesecloth. e specimens shall be subjected to 20 discharges. e interval between successive discharges shall be 5s. e UAC shall be maintained for 2min after the last discharge. E UAC shall be maintained for 2min after the last discharge.  C1

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## GA3 Series Type GB Specifications and Test Methods (1)

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#### Complement of Test Method

#### 1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods".

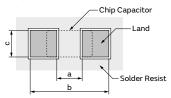
The specimen should be soldered by the conditions as described below.

Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

#### (1) Test Substrate A

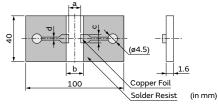
Land Dimensions



Part Number	Dimension (mm)				
	a	ь	С		
GA355	4.5	8.0	5.6		

- Material: Glass Epoxy Board
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm

#### (2) Test Substrate B

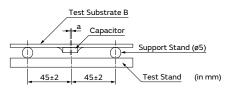


Part Number	Dimension of Pattern (mm)				
Part Number	a	b	С	d	
GA355	4.5	8.0	5.6	1.0	

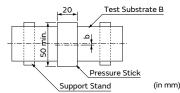
- Material: Glass Epoxy Board
- Thickness of Copper Foil: 0.035mm

#### 2. Test Method of Substrate Bending Test

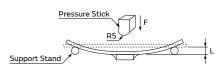
(a) Support State



(b) Test State



- a:  $\pm 2$  gap between support stand center and test stand
- b: ±5 gap between support stand center and test stand center
- Material of Test Stand and Pressure Stick
  - The material shoud be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized.
- Pressurizing Speed
  - The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



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Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / Acquired certifications of UL60950-1

## GA3 Series Type GD







## **UL60950-1 Certified Product**

#### **Features**

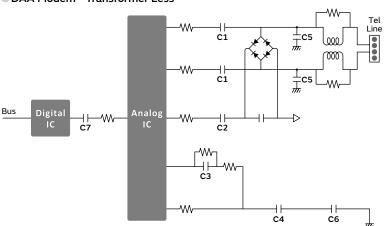
1 International Standard (IEC60384-14) certified product.

Please down load Safety Standard Certification (Type GD) from here.



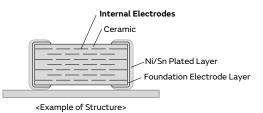
2 Can be uesd for UL60950-1 devices.

DAA Modem - Transformer Less



No.	Application	Recommend MLCC Type
C5	Lighting Surge Absorption	
C6	Noise Immunity	Type: GD / GF
C7	D/A Isolation Barrier	

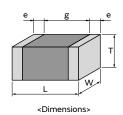
3 Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.



4) This product is only for reflow soldering.

### Specifications

Size (mm)	4.5×2.0mm to 4.5×3.2mm
Rated Voltage	250Vac
Capacitance	10pF to 4700pF
Main Applications	Modem



GND

This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.

## GA3 Series Type GD Temperature Compensating Type Part Number List

#### 4.5×2.0mm

T max.	Rated Voltage	TC Code	Сар.	Tol.	Part Number	p*
1.0mm	250Vac	SL	10pF	±5%	GA342A1XGD100JW31#	p199
			12pF	±5%	GA342A1XGD120JW31#	p199
			15pF	±5%	GA342A1XGD150JW31#	p199
			18pF	±5%	GA342A1XGD180JW31#	p199
			22pF	±5%	GA342A1XGD220JW31#	p199
			27pF	±5%	GA342A1XGD270JW31#	p199
			33pF	±5%	GA342A1XGD330JW31#	p199
			39pF	±5%	GA342A1XGD390JW31#	p199
			47pF	±5%	GA342A1XGD470JW31#	p199
			56pF	±5%	GA342A1XGD560JW31#	p199
			68pF	±5%	GA342A1XGD680JW31#	p199
			82pF	±5%	GA342A1XGD820JW31#	p199

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## GA3 Series Type GD High Dielectric Constant Type Part Number List

## 4.5×2.0mm

T max.	Rated Voltage	TC Code	Сар.	Tol.	Part Number	p*
1.5mm	250Vac	X7R	100pF	±10%	GA342QR7GD101KW01#	p203
			150pF	±10%	GA342QR7GD151KW01#	p203
			220pF	±10%	GA342QR7GD221KW01#	p203
			330pF	±10%	GA342QR7GD331KW01#	p203
			470pF	±10%	GA342QR7GD471KW01#	p203
			680pF	±10%	GA342QR7GD681KW01#	p203
			1000pF	±10%	GA342QR7GD102KW01#	p203

1500pF ±10% **GA342QR7GD152KW01#** p203

#### 4.5×3.2mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	p*
1.5mm	250Vac	X7R	1800pF	±10%	GA343QR7GD182KW01#	p203
			2200pF	±10%	GA343QR7GD222KW01#	p203
2.0mm	250Vac	X7R	4700pF	±10%	GA343DR7GD472KW01#	p203

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GA2

## GA3 Series Type GD Specifications and Test Methods (1)

No	lt	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)			
1	Appearance		No defects or abnormalities.	Visual inspection.			
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.			
3			No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC1500V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.			
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p			
5	Insulation Resistance (I.R.)		6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature			
6	Capacitance		Shown in Rated value.				
7	Q		C ≥ 30pF: 1000 or more C < 30pF: 400+20C or more C: Nominal Capacitance (pF)	Measurement Temperature: Room Temperature Measurement Frequency: 1.0±0.1MHz Measurement Voltage: AC1.0±0.2V (r.m.s.)			
8	Temperature Characteristi of Capacitano		1X: +350 to -1000 ppm/°C (Temp.Range:+20 to +85°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage.  Capacitance value as a reference is the value in step 3.    Step   Temperature (°C)			
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in			
		Capacitance	Within the specified initial value.	"Complement of Test Method".			
9	Vibration	Q	Within the specified initial value.	Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).			
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.			
		Appearance	No defects or abnormalities.	Test Method: Solder bath method			
	Resistance to	Capacitance Change	Within±2.5% or ±0.25pF (Whichever is larger)	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s			
11	Soldering	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.			
	Heat	Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.  Preheat: GA342 size: 100 to 120°C for 1min  and 170 to 200°C for 1min			
12	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".  10N, 10±1s  Applied Direction: In parallel with the test substrate and vertical with the capacitor side.			
13	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method".  Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method".  Flexure: 1mm  Holding Time: 5±1s  Soldering Method: Reflow soldering			

 $<sup>^{\</sup>star}$  Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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## GA3 Series Type GD Specifications and Test Methods (1)

Continued from the preceding page.

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)		
		Appearance Capacitance Change	No defects or abnormalities.  Within ±2.5% or ±0.25pF (Whichever is larger)	Fix the capacitor to the supporting test substrate A (glass epoxy board) shown in "Complement of Test Method"  Perform the 5 cycles according to the four heat treatments		
	Temperature Sudden Change	Q	Within the specified initial value.	shown in the following table.  Step Temp. (°C) Time (min)		
14		I.R.	3000MΩ or more	1 Min. Operating Temp. +0/-3 30±3		
		Voltage Proof	No defects.	2         Room Temp.         2 to 3           3         Max. Operating Temp. +3/-0         30±3           4         Room Temp.         2 to 3   Exposure Time: 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
	High	Capacitance Change	Within ±5.0% or ±0.5pF (Whichever is larger)	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.		
15	Temperature High Humidity	Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.12 Adhesive Strength of Termination (apply force: 5N) No.13 Substrate Bending Test Test Temperature: 40±2°C Test Humidity: 90 to 95%RH		
	(Steady)	I.R.	3000MΩ or more	Test Time: 500+24/-0h.		
		Voltage Proof	No defects.	Applied Voltage: Rated voltage Exposure Time:24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
		Capacitance Change	Within ±3.0% or ±0.3pF (Whichever is larger)	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  • No.12 Adhesive Strength of Termination (apply force: 5N)		
	Durability	Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.13 Substrate Bending Test Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 2.5kV Impulse		
		I.R.	3000M $Ω$ or more	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.		
16		y Voltage Proof	I NO DETECTS	Front time (T1) = $1.2\mu$ s= $1.67T$ Time to half-value (T2) = $50\mu$ s Apply voltage as Table for 1000h at $125+2/-0^{\circ}$ C, relative		
				humidity 50% max.  Applied voltage  AC425V (r.m.s.), except that once each hour the voltage		
				is increased to AC1000V (r.m.s.) for 0.1s.		
17	1.7 Passive Flammability		The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	Exposure Time: 24±2h at room condition*.  The capacitor under test shall be held in the flame in the position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min.  Approximately 8mm Buner  Approximately 8mm  Approximate		
				Wood Board of Approximately 10mm in Thickness		
* D		T 1	5 to 35°C Relative humidity: 45 to 75% Atmosphere pr	Acceptant OC to 10Cl/Da		

 $<sup>{\</sup>rm ^*Room\ Condition:}\ Temperature: 15\ to\ 35^\circ C,\ Relative\ humidity: 45\ to\ 75\%,\ Atmosphere\ pressure: 86\ to\ 106 kPa$ 

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## GA3 Series Type GD Specifications and Test Methods (1)

Continued from the preceding page.

No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
			The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth.  The specimens shall be subjected to 20 discharges.  The interval between successive discharges shall be 5s.  The UAC shall be maintained for 2min after the last discharge.
			$\begin{array}{c ccccccccccccccccccccccccccccccccccc$
			C1, C2: Filter capacitor 1µF±10%
18	Active Flammability	The cheesecloth shall not be on fire.	C3: Capacitor 0.033μF±5% L1 to L4: Rod coa choke 1.5mH±20%, 16A R: Resistor 100Ω±2% Cx < 0.068μF Ct: Tank capacitor 3μF±5% 10kV Cx ≦ 1μF U-: UR±5% UR: Rated voltage Cx: Capacitor under test F: Slow-blow fuse, rated 16A Ut: Voltage to which the tank capacitor Ct is charged
			time

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GA2

GA3 GF

GR7

GA3 GB

KR3

GMA

## GA3 Series Type GD Specifications and Test Methods (1)

Continued from the preceding page.

#### Complement of Test Method

1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods".

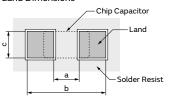
The specimen should be soldered by the conditions as described below.

Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

#### (1) Test Substrate A

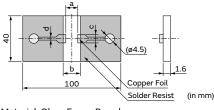
Land Dimensions



Dank Number	Dimension (mm)			
Part Number	a	ь	С	
GA342	3.5	7.0	2.4	

- Material: Glass Epoxy Board
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm

#### (2) Test Substrate B

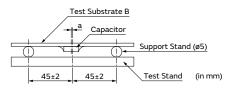


Davit Niveshau	Dimension of Pattern (mm)					
Part Number	a	b	С	d		
GA342	3.5	7.0	2.4	1.0		

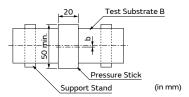
- Material: Glass Epoxy Board
- Thickness of Copper Foil: 0.035mm

#### 2. Test Method of Substrate Bending Test

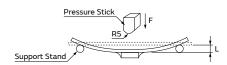
(a) Support State



(b) Test State



- a: ±2 gap between support stand center and test stand
- b:  $\pm 5$  gap between support stand center and test stand center
- Material of Test Stand and Pressure Stick
- The material shoud be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized.
- Pressurizing Speed
  - The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



## GA3 Series Type GD Specifications and Test Methods (2)

No	Ite	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)	
1	Appearance		No defects or abnormalities.	Visual inspection.	
2	2 Dimension		Within the specified dimensions.	Using calipers and micrometers.	
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC1500V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.	
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p	
5	Insulation Res	sistance (I.R.)	$6000$ M $\Omega$ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature	
6	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature	
7	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)	
8	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage.  Capacitance value as a reference is the value in step 3.    Step	
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in	
9	Vibration	D.F.	Within the specified initial value.  Within the specified initial value.	"Complement of Test Method".  Kind of Vibration: A simple harmonic motion  10Hz to 55Hz to 10Hz (1min)  Total amplitude: 1.5mm  This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).	
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.	
		Appearance	No defects or abnormalities.	Test Method: Solder bath method	
		Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s	
	Resistance to	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.	
11	to Soldering Heat	Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.  Preheat: GA342/43 size: 100 to 120°C for 1min and 170 to 200°C for 1min  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.	
12	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".  10N, 10±1s  Applied Direction: In parallel with the test substrate and vertical with the capacitor side.	

<sup>\*</sup> Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

Continued on the following page. 🖊

GRM

GA2

203

KR3

## GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page.  $\searrow$ 

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)		
13	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method".  Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method"  Flexure: 1mm  Holding Time: 5±1s  Soldering Method: Reflow soldering		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epoxy		
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method".  Perform the 5 cycles according to the four heat treatments shown in the following table.		
		D.F.	0.05 max.	Step Temp. (°C) Time (min)		
	Temperature	I.R.	$3000$ M $\Omega$ or more	1 Min. Operating Temp. +0/-3 30±3		
14	Sudden Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3  Exposure Time: 24±2h at room condition*.  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  • No.12 Adhesive Strength of Termination (apply force: 5N)		
	High	D.F.	0.05 max.	No.13 Substrate Bending Test		
15	Temperature High Humidity (Steady)	I.R.	$3000$ M $\Omega$ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH		
		Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
		Capacitance Change	Within ±20%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  • No.12 Adhesive Strength of Termination (apply force: 5N)		
		D.F.	0.05 max.	No.13 Substrate Bending Test		
		I.R.	$3000$ M $\Omega$ or more	Next, Impulse Voltage test is performed.  Each individual capacitor shall be subjected to a 2.5kV Impulse		
16	Durability	Voltage Proof	No defects.	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.  100 (%) 90 50 Tront time (T1) = 1.2 \mu s=1.67T Time to half-value (T2) = 50 \mu s  Apply voltage as Table for 1000h at 125+2/-0°C, relative humidity 50% max.  Applied Voltage AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s.  Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		

<sup>\*</sup> Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

Continued on the following page. 🖊

## GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page

lo Item	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
.7 Passive Flammability	The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning.  Each specimen shall only be exposed once to the flame.  Time of exposure to flame: 30s  Length of flame: 12±1mm  Gas burner: Length 35mm min.  Inside dia: 0.5±0.1mm  Outside dia: 0.9mm max.  Gas: Butane gas purity 95% min.  Test Specimen  Approximately 8mm  Flame  200±5mm  Wood Board of Approximately 10mm in Thickness
8 Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $\frac{S1}{C} = \frac{1}{C} = \frac$

GR3

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GA3 GB

GA3 GF

NFΛ

time

GA3 GF

GA2

## GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page.

#### Complement of Test Method

1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods".

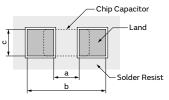
The specimen should be soldered by the conditions as described below.

Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

#### (1) Test Substrate A

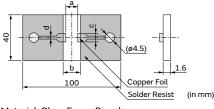
Land Dimensions



Part Number	Dimension (mm)			
Part Number	a	ь	С	
GA342	3.5	7.0	2.4	
GA343	3.5	7.0	3.7	

- Material: Glass Epoxy Board
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm

#### (2) Test Substrate B

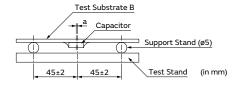


Dawk Niveshau	Dimension of Pattern (mm)				
Part Number	a	b	С	d	
GA342	3.5	7.0	2.4	1.0	
GA343	3.5	7.0	3.7	1.0	

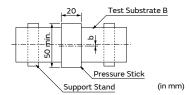
- Material: Glass Epoxy Board
- Thickness of Copper Foil: 0.035mm

#### 2. Test Method of Substrate Bending Test

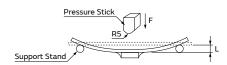
(a) Support State



(b) Test State



- a:  $\pm 2$  gap between support stand center and test stand
- b:  $\pm 5$  gap between support stand center and test stand center
- Material of Test Stand and Pressure Stick
- The material shoud be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized.
- Pressurizing Speed
  - The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / Acquired certifications of IEC60384-14 Class X1/Y2 and UL60950-1

## GA3 Series Type GF







Size 4.5x2.0mm: This product is applicable only for the instruments certified by EN/IEC60950-1

Size 5.7x2.8mm or 5.7x5.0mm: This product is applicable as X or Y capacitor

#### **Features**

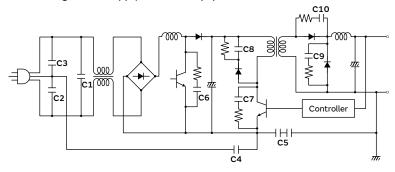
1 International Standard (IEC60384-14) certified product.

Please down load Safety Standard Certification (Type GF: X1/Y2) from here.



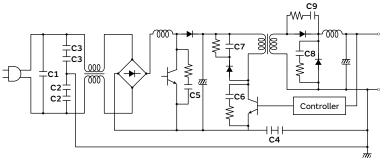
2 Can be used as a Class Y2 capacitor.

Switching Power Supply - Class 1 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2		
С3	Y Cap	Type: GF
C4		
C5	Primary - Secondary Coupling	Type: GF×2

Switching Power Supply - Class 2 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2	Y Cap	
С3	т Сар	Type: GF×2
C4	Primary - Secondary Coupling	

GRM

GR3

GRJ

GR4

GR7

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GQM

GA2

A3 GD

> SA3 G

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NFM

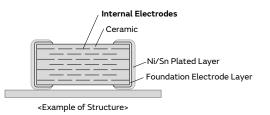
33 // R

GMA K

Caution GMI

GMA

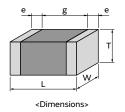
3 Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.



4 This product is only for reflow soldering.

## Specifications

Size (mm)	4.5×2.0mm to 5.7×5.0mm
Rated Voltage	250Vac
Capacitance	10pF to 4700pF
Main Applications	AC-DC power supply



This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.

## GA3 Series Type GF Temperature Compensating Type Part Number List

#### 4.5×2.0mm

T max.	Rated Voltage	TC Code	Сар.	Tol.	Part Number	p*
1.0mm	250Vac	SL	10pF	±5%	GA342A1XGF100JW31#	p211
			12pF	±5%	GA342A1XGF120JW31#	p211
			15pF	±5%	GA342A1XGF150JW31#	p211
			18pF	±5%	GA342A1XGF180JW31#	p211
			22pF	±5%	GA342A1XGF220JW31#	p211
			27pF	±5%	GA342A1XGF270JW31#	p211
			33pF	±5%	GA342A1XGF330JW31#	p211
			39pF	±5%	GA342A1XGF390JW31#	p211
			47pF	±5%	GA342A1XGF470JW31#	p211
			56pF	±5%	GA342A1XGF560JW31#	p211
			68pF	±5%	GA342A1XGF680JW31#	p211
			82pF	±5%	GA342A1XGF820JW31#	p211

GA3 Series Type GF High Dielectric Constant Type Part Number List

GJM

210

## 4.5×2.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	p*
1.5mm	250Vac	X7R	100pF	±10%	GA342QR7GF101KW01#	p215
			150pF	±10%	GA342QR7GF151KW01#	p215
			470pF	±10%	GA342QR7GF471KW01#	p215
			680pF	±10%	GA342QR7GF681KW01#	p215
2.2mm	250Vac	X7R	220pF	±10%	GA342DR7GF221KW02#	p215
			330pF	±10%	GA342DR7GF331KW02#	p215
			1000pF	±10%	GA342DR7GF102KW02#	p215

### 5.7×2.8mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	p*
1.5mm	250Vac	X7R	100pF	±10%	GA352QR7GF101KW31#	p215
			150pF	±10%	GA352QR7GF151KW31#	p215
			220pF	±10%	GA352QR7GF221KW31#	p215
			330pF	±10%	GA352QR7GF331KW31#	p215
			470pF	±10%	GA352QR7GF471KW01#	p215
			680pF	±10%	GA352QR7GF681KW01#	p215
			1000pF	±10%	GA352QR7GF102KW01#	p215
			1500pF	±10%	GA352QR7GF152KW01#	p215

### 5.7×5.0mm

T max.	Rated Voltage	TC Code	Сар.	Tol.	Part Number	р*
1.5mm	250Vac	X7R	1800pF	±10%	GA355QR7GF182KW01#	p215
			2200pF	±10%	GA355QR7GF222KW01#	p215
			3300pF	±10%	GA355QR7GF332KW01#	p215
2.0mm	250Vac	X7R	4700pF	±10%	GA355DR7GF472KW01#	p215

GRM

Ω Σ

GQM

GA2

GA3 GD

## GA3 Series Type GF Specifications and Test Methods (1)

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)			
1	Appearance		No defects or abnormalities.	Visual inspection.			
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.			
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC2000V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.			
4	Impulse Volta	ge	No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p			
5	Insulation Res	sistance (I.R.)	6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature			
6	Capacitance		Shown in Rated value.				
7	Q		C ≧ 30pF: 1000 or more C < 30pF: 400+20C or more C: Nominal Capacitance (pF)	Measurement Temperature: Room Temperature Measurement Frequency: 1.0±0.1MHz Measurement Voltage: AC1.0±0.2V (r.m.s.)			
8	Temperature Characteristics of Capacitance		1X: +350 to -1000 ppm/°C (Temp.Range:+20 to +85°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage.  Capacitance value as a reference is the value in step 3.  Step Temperature (°C)  1 Reference Temp. ±2  2 Min. Operating Temp. ±3  3 Reference Temp. ±2  4 Max. Operating Temp. ±3  5 Reference Temp. ±2  However, the capacitance shall be measured at even 85°C between step 3 and step 4.			
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in			
		Capacitance	Within the specified initial value.	"Complement of Test Method".			
9	Vibration	Q	Within the specified initial value.	Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).			
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.			
		Appearance	No defects or abnormalities.	Test Method: Solder bath method			
	Resistance to	Capacitance Change	Within±2.5% or ±0.25pF (Whichever is larger)	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s			
11	Soldering	I.R.	1000M $\Omega$ or more	Immersing in speed: 25±2.5mm/s.			
	Heat	Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.  Preheat: GA342 size: 100 to 120°C for 1min  and 170 to 200°C for 1min			
12	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".  10N, 10±1s  Applied Direction: In parallel with the test substrate and vertical with the capacitor side.			
13	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method".  Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method".  Flexure: 1mm  Holding Time: 5±1s  Soldering Method: Reflow soldering			

<sup>\*</sup> Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

Ω

GA3 GB

KR3

## GA3 Series Type GF Specifications and Test Methods (1)

Continued from the preceding page.

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)				
		Appearance Capacitance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epoxy board) shown in "Complement of Test Method".				
	Temperature Sudden	Change	Within ±2.5% or ±0.25pF (Whichever is larger)	Perform the 5 cycles according to the four heat treatments shown in the following table.				
14		Q I.R.	Within the specified initial value. 3000MΩ or more	Step   Temp. (°C)   Time (min)				
	Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3  Exposure Time: 24±2h at room condition*.				
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy				
	High	Capacitance Change	Within ±5.0% or ±0.5pF (Whichever is larger)	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.				
15	Temperature High Humidity (Steady)	Q	C ≥ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.12 Adhesive Strength of Termination (apply force: 5N) No.13 Substrate Bending test Test Temperature: 40±2°C Test Humidity: 90 to 95%RH				
	(Steady)	I.R.	3000MΩ or more	Test Time: 500+24/-0h Applied Voltage: Rated voltage				
		Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.				
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass e board) shown in "Complement of Test Method".				
		Capacitance Change	Within ±3.0% or ±0.3pF (Whichever is larger)	Before this test, the test shown in the following is performed.  • No.12 Adhesive Strength of Termination (apply force: 5N)				
		Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.13 Substrate Bending test Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 5kV Impulse				
		I.R.	3000MΩ or more	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.				
16	Durability	Voltage Proof	Voltage No defects	100 (%) 90 50 30 0 t Front time (T1) = 1.2μs=1.67T Time to half-value (T2) = 50μs				
				Apply voltage as Table for 1000h at 125+2/-0°C , relative humidity 50% max.  Applied voltage				
				AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s.				
				Exposure Time: 24±2h at room condition*.				
17	7 Passive Flammability		The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning.  Each specimen shall only be exposed once to the flame.  Time of exposure to flame: 30s  Length of flame: 12±1mm  Gas burner: Length 35mm min.  Inside dia: 0.5±0.1mm  Outside dia: 0.9mm max.  Gas: Butane gas purity 95% min.  Test Specimen				
								Approximately 8mm  Buner Flame 200±5mm
				———— Tissue Paper				

 $<sup>{\</sup>rm ^*Room\ Condition:}\ Temperature: 15\ to\ 35^\circ C,\ Relative\ humidity: 45\ to\ 75\%,\ Atmosphere\ pressure: 86\ to\ 106 kPa$ 

Continued on the following page. 🖊

## GA3 Series Type GF Specifications and Test Methods (1)

Continued from the preceding page.

No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
			The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth.  The specimens shall be subjected to 20 discharges.  The interval between successive discharges shall be 5s.  The UAC shall be maintained for 2min after the last discharge.
18	Active Flammability	The cheesecloth shall not be on fire.	C1, C2: Filter capacitor $1\mu F \pm 10\%$ C3: Capacitor $0.033\mu F \pm 5\%$ L1 to L4: Rod coa choke $1.5mH \pm 20\%$ , $16A$ R: Resistor $100\Omega \pm 2\%$ Cx < $0.068\mu F$ Ct: Tank capacitor $3\mu F \pm 5\%$ $10kV$ Cx $\leq 1\mu F$ U-: UR $\pm 5\%$ UR: Rated voltage Cx: Capacitor under test F: Slow-blow fuse, rated $16A$ Ut: Voltage to which the tank capacitor Ct is charged
			time

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## GA3 Series Type GF Specifications and Test Methods (1)

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#### Complement of Test Method

1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods".

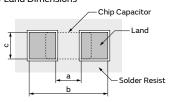
The specimen should be soldered by the conditions as described below.

Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

#### (1) Test Substrate A

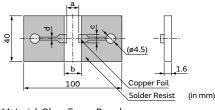
Land Dimensions



	D	imension (mm	1)
Part Number	a	ь	С
GA342	3.5	7.0	2.4

- Material: Glass Epoxy Board
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm

#### (2) Test Substrate B

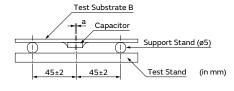


Daut Namahau	Din	nension of	Pattern (m	ım)
Part Number	a	b	С	d
GA342	3.5	7.0	2.4	1.0

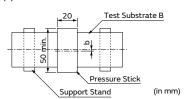
- Material: Glass Epoxy Board
- Thickness of Copper Foil: 0.035mm

#### 2. Test Method of Substrate Bending Test

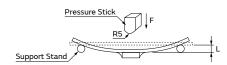
(a) Support State



(b) Test State



- a: ±2 gap between support stand center and test stand
- b:  $\pm 5$  gap between support stand center and test stand center
- Material of Test Stand and Pressure Stick
- The material should be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized.
- Pressurizing Speed
  - The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



## GA3 Series Type GF Specifications and Test Methods (2)

No	ltem		Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)	
1	Appearance		No defects or abnormalities.	Visual inspection.	
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.	
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC2000V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.	
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p	
5	Insulation Resistance (I.R.)		$6000$ M $\Omega$ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Charge/discharge current: 50mA max. Measurement Temperature: Room Temperature	
6	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature	
7	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)	
8	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage.  Capacitance value as a reference is the value in step 3.    Step	
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in	
		Capacitance	Within the specified initial value.	"Complement of Test Method".  Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min)  Total amplitude: 1.5mm  This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).	
9	Vibration	D.F.	Within the specified initial value.		
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.	
		Appearance	No defects or abnormalities.	Test Method: Solder bath method	
	Resistance to Soldering Heat	Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s	
		I.R.	1000M $\Omega$ or more	Immersing in speed: 25±2.5mm/s.	
11		Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.  Preheat: GA342/52/55 size: 100 to 120°C for 1min and 170 to 200°C for 1min  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.	
12	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".  10N, 10±1s  Applied Direction: In parallel with the test substrate and vertical with the capacitor side.	

 $<sup>{\</sup>rm ^*\,Room\,Condition:\,Temperature:\,15\,to\,35^{\circ}C,\,Relative\,humidity:\,45\,to\,75\%,\,Atmosphere\,pressure:\,86\,to\,106kPa}$ 

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## GA3 Series Type GF Specifications and Test Methods (2)

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No Item		Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)		
Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method".  Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method".  Flexure: 1mm  Holding Time: 5±1s  Soldering Method: Reflow soldering		
	Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epoxy		
Temperature Sudden Change	Capacitance Change	Within±15%	board) shown in "Complement of Test Method".  Perform the 5 cycles according to the four heat treatments shown in the following table.		
	D.F.	0.05 max.	Step Temp. (°C) Time (min)		
	I.R.	3000M $Ω$ or more	1 Min. Operating Temp. +0/-3 30±3		
	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3  Exposure Time: 24±2h at room condition*.  • Pretreatment  Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
	Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
	Capacitance Change	Within±15%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  No.12 Adhesive Strength of Termination (apply force: 5N)		
High	D.F.	0.05 max.	No.13 Substrate Bending Test		
	I.R.	$3000$ M $\Omega$ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH		
Humidity (Steady)	Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
	Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy		
	Capacitance Change	Within ±20%	board) shown in "Complement of Test Method".  Before this test, the test shown in the following is performed.  No.12 Adhesive Strength of Termination (apply force: 5N)  No.13 Substrate Bending Test  North Empires Veltage test in performed.		
	D.F.	0.05 max.			
Durability	I.R.	$3000$ M $\Omega$ or more	Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 5kV Impulse		
	rability  Voltage Proof	No defects.	(the voltage value means zero to peak) for 3 times.  Then the capacitors are applied to life test.  100 (%) 90 50 Front time (T1) = 1.2µs=1.67T Time to half-value (T2) = 50µs  Apply voltage as Table for 1000h at 125+2/-0°C, relative humidity 50% max.  Applied Voltage AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s.  Exposure Time: 24±2h at room condition*.  • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
	Substrate Bending Test  Temperature Sudden Change  High Humidity (Steady)  Durability	Substrate Bending Test  Appearance Capacitance Change D.F.  I.R.  Voltage Proof  Appearance Capacitance Change D.F.  I.R.  Voltage Proof  Appearance Capacitance Change D.F.  I.R.  I.R.  Durability  Voltage Proof  Appearance Capacitance Change D.F.  I.R.  Voltage Proof  Appearance Capacitance Change D.F. I.R.	Substrate Bending Test  Appearance No defects or abnormalities.  Capacitance Change D.F. 0.05 max.  I.R. 3000 MΩ or more  Voltage Proof No defects.  Appearance No defects or abnormalities.  Capacitance Change No defects.  Appearance No defects.  Capacitance Change Within±15%  D.F. 0.05 max.  I.R. 3000 MΩ or more  Appearance Within±15%  D.F. 0.05 max.  I.R. 3000 MΩ or more  Appearance No defects.  Voltage Proof No defects.  Appearance No defects.  Voltage Proof No defects.  Appearance No defects or abnormalities.  Capacitance Change No defects.  L.R. 3000 MΩ or more  Appearance No defects or abnormalities.  Capacitance Change O.F. 0.05 max.  I.R. 3000 MΩ or more  Voltage No defects.		

 $<sup>{\</sup>rm ^*\,Room\,Condition:\,Temperature:\,15\,to\,35^\circ C,\,Relative\,humidity:\,45\,to\,75\%,\,Atmosphere\,pressure:\,86\,to\,106 kPa}$ 

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## GA3 Series Type GF Specifications and Test Methods (2)

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No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)			
17	Passive Flammability	The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning.  Each specimen shall only be exposed once to the flame.  Time of exposure to flame: 30s  Length of flame: 12±1mm  Gas burner: Length 35mm min.  Inside dia: 0.5±0.1mm  Outside dia: 0.9mm max.  Gas: Butane gas purity 95% min.  Approximately 8mm  Buner  Flame  200±5mm  Tissue Paper  Wood Board of Approximately 10mm in Thickness			
188	Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $\begin{array}{cccccccccccccccccccccccccccccccccccc$			

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## GA3 Series Type GF Specifications and Test Methods (2)

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#### **Complement of Test Method**

1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods".

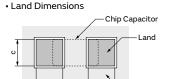
The specimen should be soldered by the conditions as described below.

Solder Resist

Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

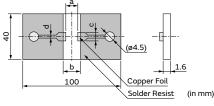
(1) Test Substrate A



Part Number	Dimension (mm)		
Part Number	a	ь	С
GA342	3.5	7.0	2.4
GA352	4.5	8.0	3.2
GA355	4.5	8.0	5.6

- Material: Glass Epoxy Board
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm

#### (2) Test Substrate B

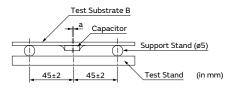


Davit Niveshau	Dimension of Pattern (mm)			
Part Number	a	b	С	d
GA342	3.5	7.0	2.4	1.0
GA352	4.5	8.0	3.2	1.0
GA355	4.5	8.0	5.6	1.0

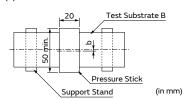
- Material: Glass Epoxy Board
- Thickness of Copper Foil: 0.035mm

#### 2. Test Method of Substrate Bending Test

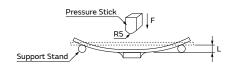
(a) Support State



(b) Test State



- a: ±2 gap between support stand center and test stand
- b:  $\pm 5$  gap between support stand center and test stand center
- Material of Test Stand and Pressure Stick
- The material should be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized.
- Pressurizing Speed
  - The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



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GA342D1XGF220JY02L GA342DR7GD102KW02L GA342DR7GD151KW02L GA342QR7GD101KW01L
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